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Call For Papers **ATS'08**

The Seventeenth Asian Test Symposium

November 24-27, 2008, Keio Plaza Hotel Sapporo, Sapporo, JAPAN

Sponsored by

IEEE Computer Society

Test Technology Technical Council

The IEICE Information and Systems Society, Technical Committee on DC

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SCOPE

The Asian Test Symposium (ATS) provides an international forum for engineers and researchers from all countries of the world, especially from Asia, to present and discuss various aspects of device, board and system testing with design, manufacturing and field considerations in mind. The official language of the symposium is English. Topics of interest include, but are not limited to:

- Automatic Test Generation / Fault Simulation
- Design for Testability / Synthesis for Testability
- Built-In Self-Test / Test Data Compression
- Delay Testing
- Defect-Based Testing / IDDX Testing
- Power Issues in Test
- Fault Modeling & Diagnosis
- Memory Test / FPGA Test
- Analog and Mixed-Signal Test
- RF Testing / High-Speed I/O Test
- System-on-a-Chip Test
- Board and System Test
- Network Protocol Testing
- Design Verification and Validation
- On-Line Test
- Fault Tolerance / Dependable System
- Software Testing / Software Design for Testing
- Economics of Test

SUBMISSIONS

Regular Session: The ATS'08 Program Committee invites original, unpublished paper submissions for ATS'08. Paper submissions should be complete manuscripts, not exceeding six pages (including figures, tables, and bibliography) in a standard IEEE two-column format. Authors should clearly explain the significance of the work, highlight novel features, and describe its current status. On the title page, please include: author name(s) and affiliation(s), and the mailing address, phone number, fax number, and e-mail address of the contact author. An abstract of 50 words or less and 5-10 keywords are also required. All submissions are to be made electronically through the ATS'08 website. Detailed instructions for submissions are to be found at the ATS'08 website. Electronic submissions in PDF files are strongly recommended. The submission will be considered evidence that upon acceptance the author(s) will prepare the final manuscript (six pages for regular session) in time for inclusion in the proceedings and will present the paper at the Symposium.

Industry Session: This session will address a wide range of practical problems in LSI test, board and system test, diagnosis, failure analysis, design verification, and so on. The session will consist of brief oral presentations followed by poster presentations. A one-page abstract is required for submission. Each submission should also include the complete address and designate a contact person and a presenter. Abstract submissions should be emailed to Industry Chair (ats08-ic@dsgn.im.hiroshima-cu.ac.jp).

KEY DATES (Regular Session)

Submission deadline: May 19, 2008
Notification of acceptance: July 11, 2008
Camera ready copy: August 11, 2008

KEY DATES (Industry Session)

Submission deadline: June 23, 2008
Notification of acceptance: July 11, 2008
Camera ready copy (one page): August 11, 2008

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